

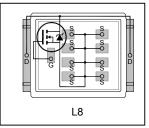
#### **AUTOMOTIVE GRADE**

### Advanced Process Technology

- Optimized for Automotive Motor Drive, DC-DC and other Heavy Load Applications
- Exceptionally Small Footprint and Low Profile
- High Power Density
- Low Parasitic Parameters
- Dual Sided Cooling
- 175°C Operating Temperature
- Repetitive Avalanche Capability for Robustness and Reliability
- Lead free, RoHS and Halogen free
- Automotive Qualified \*

Automotive DirectFET® Power MOSFET ②

V <sub>(BR)DSS</sub>	100V
R <sub>DS(on)</sub> typ.	$3.5$ m $\Omega$
max.	4.4m $Ω$
D (Silicon Limited)	114A
Q <sub>g (typical)</sub>	81nC





Applicable DirectFET® Outline and Substrate Outline ①

SB   SC     M2   M4   L4   L6	SB	SC			M2	M4		L4	L6	L8	
-------------------------------	----	----	--	--	----	----	--	----	----	----	--

#### Description

The AUIRF7669L2TR combines the latest Automotive HEXFET® Power MOSFET Silicon technology with the advanced DirectFETTM packaging to achieve the lowest on-state resistance in a package that has the footprint of a DPak (TO-252AA) and only 0.7 mm profile. The DirectFET package is compatible with existing layout geometries used in power applications, PCB assembly equipment and vapor phase, infra-red or convection soldering techniques, when application note AN-1035 is followed regarding the manufacturing methods and processes. The DirectFET package allows dual sided cooling to maximize thermal transfer in automotive power systems.

This HEXFET® Power MOSFET is designed for applications where efficiency and power density are essential. The advanced DirectFET packaging platform coupled with the latest silicon technology allows the AUIRF7669L2TR to offer substantial system level savings and performance improvement specifically in motor drive, high frequency DC-DC and other heavy load applications on ICE, HEV and EV platforms. This MOSFET utilizes the latest processing techniques to achieve low on-resistance and low Qg per silicon area. Additional features of this MOSFET are 175°C operating junction temperature and high repetitive peak current capability. These features combine to make this MOSFET a highly efficient, robust and reliable device for high current automotive applications..

Book Bort Number	Dookogo Tyro	Standard	Standard Pack	
Base Part Number	Package Type	Form	Quantity	Orderable Part Number
AUIRF7669L2	DirectFET Large Can	Tape and Reel	4000	AUIRF7669L2TR

#### **Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

	Parameter	Max.	Units
$V_{DS}$	Drain-to-Source Voltage	100	V
$V_{GS}$	Gate-to-Source Voltage	±20	V
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited) @	114	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited) 4	81	
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited) 3	19	Α
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	375	
I <sub>DM</sub>	Pulsed Drain Current ©	460	
$P_D @ T_C = 25^{\circ}C$	Power Dissipation ④	100	10/
$P_D @ T_A = 25^{\circ}C$	Power Dissipation ③	3.3	W
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally Limited) ®	260	I
E <sub>AS (tested)</sub>	Single Pulse Avalanche Energy (Tested Value) ⑤	850	mJ
I <sub>AR</sub>	Avalanche Current ®	Coo Fig. 16, 17, 10a, 10b	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ⑤	See Fig. 16, 17, 18a, 18b	mJ
T <sub>P</sub>	Peak Soldering Temperature	260	
$T_J$	Operating Junction and	-55 to + 175	°C
T <sub>STG</sub>	Storage Temperature Range		

HEXFET® is a registered trademark of Infineon.

<sup>\*</sup>Qualification standards can be found at www.infineon.com



# **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JA}$	Junction-to-Ambient ③		45	
$R_{\theta JA}$	Junction-to-Ambient ®	12.5		
$R_{\theta JA}$	Junction-to-Ambient ®	20		°C/W
$R_{ heta J ext{-}Can}$	Junction-to-Can 🐠		1.2	
R <sub>0J-PCB</sub>	Junction-to-PCB Mounted		0.5	
	Linear Derating Factor 4	0	.83	W/°C

# Static Electrical Characteristics @ $T_J$ = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.08		V/°C	Reference to 25°C, I <sub>D</sub> = 1.0mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		3.5	4.4	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 68A ⑦
$V_{GS(th)}$	Gate Threshold Voltage	3.0	4.0	5.0	V	)/ - )/   - 250··A
$\Delta V_{GS(th)} / \Delta T_J$	Gate Threshold Voltage Coefficient		-13		mV/°C	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$
gfs	Forward Transconductance	90			S	$V_{DS} = 25V, I_{D} = 68A$
$R_G$	Internal Gate Resistance		1.5		Ω	
	Drain to Source Leakage Current			5.0		$V_{DS} = 100V, V_{GS} = 0V$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			250	μA	$V_{DS} = 100V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			100	n 1	V <sub>GS</sub> = 20V
	Gate-to-Source Reverse Leakage			-100	nA	V <sub>GS</sub> = -20V

## Dynamic Electrical Characteristics @ T<sub>1</sub> = 25°C (unless otherwise specified)

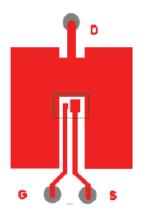
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$Q_g$	Total Gate Charge		81	120		V <sub>DS</sub> = 50V
Q <sub>gs1</sub>	Gate-to-Source Charge		23			V <sub>GS</sub> = 10V
Q <sub>gs2</sub>	Gate-to-Source Charge		6.8		0	I <sub>D</sub> = 68A
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		34		nC	See Fig.11
Q <sub>godr</sub>	Gate Charge Overdrive		17.2			
$Q_{sw}$	Switch Charge (Q <sub>gs2</sub> + Q <sub>gd</sub> )		40.8			
Q <sub>oss</sub>	Output Charge		46		nC	V <sub>DS</sub> = 16V, V <sub>GS</sub> = 0V
$t_{d(on)}$	Turn-On Delay Time		15			V <sub>DD</sub> = 50V, V <sub>GS</sub> = 10V ⑦
t <sub>r</sub>	Rise Time		30			I <sub>D</sub> = 68A
$t_{d(off)}$	Turn-Off Delay Time		27		ns	$R_G = 1.8\Omega$
t <sub>f</sub>	Fall Time		14			
C <sub>iss</sub>	Input Capacitance		5660			V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance		1140			V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance		240			f = 1.0 MHz
Coss	Output Capacitance		9250		pF	$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0 MHz$
C <sub>oss</sub>	Output Capacitance		660			$V_{GS} = 0V, V_{DS} = 80V, f = 1.0 \text{ MHz}$
Coss eff.	Effective Output Capacitance		1040			$V_{GS}$ = 0V, $V_{DS}$ = 0V to 80V

Notes  ${\mathbin{\textcircled{\tiny 1}}}$  through  ${\mathbin{\textcircled{\tiny 0}}}$  are on page 3



#### **Diode Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current			114		MOSFET symbol
IS	(Body Diode)			114	_	showing the
	Pulsed Source Current			460	A	integral reverse
ISM	(Body Diode) ©		<del></del>   460	460		p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$ , $I_S = 68A$ , $V_{GS} = 0V$ ⑦
t <sub>rr</sub>	Reverse Recovery Time		61	92	ns	$T_J = 25^{\circ}C$ , $I_F = 68A$ , $V_{DD} = 50V$
$Q_{rr}$	Reverse Recovery Charge		140	210	nC	dv/dt = 100A/µs ⑦



3 Surface mounted on 1 in. square Cu board (still air).



 Mounted to a PCB with small clip heatsink (still air)



 Mounted on minimum footprint full size board with metalized back and with small clip heatsink (still air).

- ${\mathbb O}$  Click on this section to link to the appropriate technical paper.  ${\mathbb O}$  Click on this section to link to the DirectFET  $^{\! @}$  Website.
- 3 Surface mounted on 1 in. square Cu board, steady state.
- ④ T<sub>C</sub> measured with thermocouple mounted to top (Drain) of part.
- © Repetitive rating; pulse width limited by max. junction temperature.
- ⑥ Starting  $T_J = 25$ °C, L = 0.11mH,  $R_G = 25Ω$ ,  $I_{AS} = 68$ A.
- $\ \ \$  Pulse width  $\le 400 \mu s$ ; duty cycle  $\le 2\%$ .
- ® Used double sided cooling, mounting pad with large heatsink.
- Mounted on minimum footprint full size board with metalized back and with small clip heat sink.
- @ R<sub> $\theta$ </sub> is measured at T<sub>J</sub> of approximately 90°C.

2015-11-16



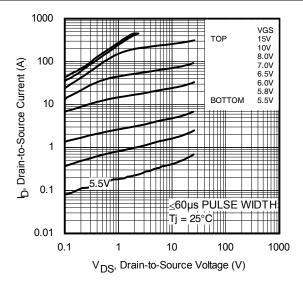


Fig. 1 Typical Output Characteristics

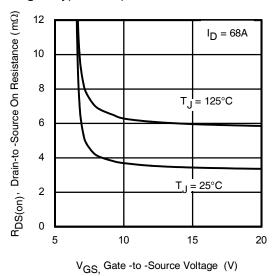


Fig. 3 Typical On-Resistance vs. Gate Voltage

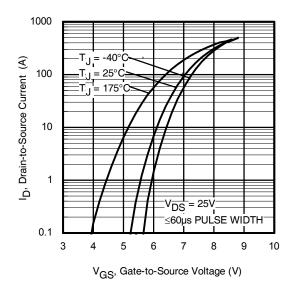


Fig 5. Typical Transfer Characteristics

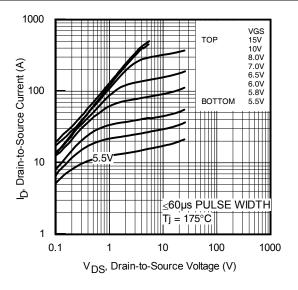


Fig. 2 Typical Output Characteristics

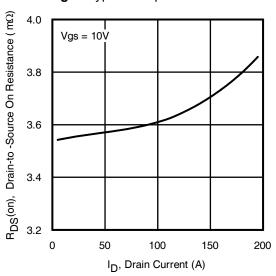


Fig. 4 Typical On-Resistance vs. Drain Current

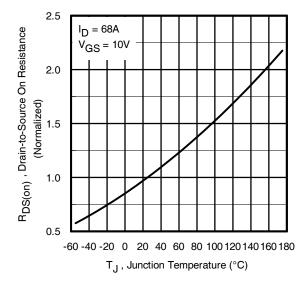
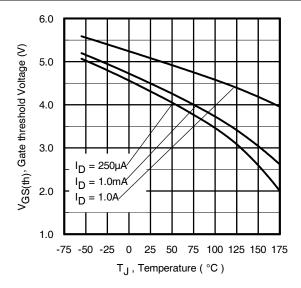


Fig 6. Normalized On-Resistance vs. Temperature

2015-11-16

4





**Fig. 7** Typical Threshold Voltage vs. Junction Temperature

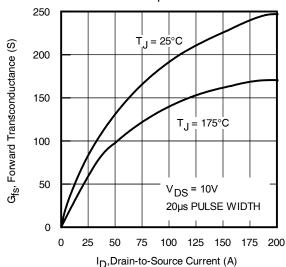
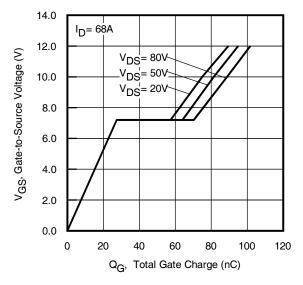


Fig 9. Typical Forward Trans conductance vs. Drain Current



**Fig 11.** Typical Gate Charge vs. Gate-to-Source Voltage

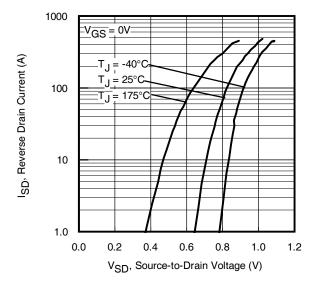


Fig 8. Typical Source-Drain Diode Forward Voltage

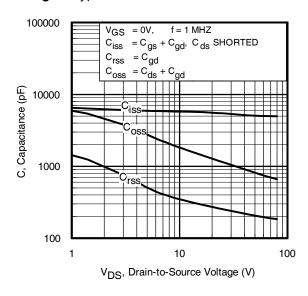


Fig 10. Typical Capacitance vs. Drain-to-Source Voltage

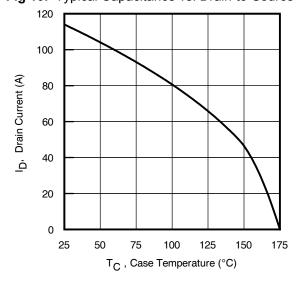
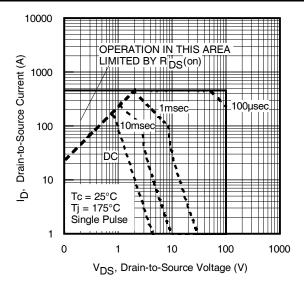


Fig 12. Maximum Drain Current vs. Case Temperature





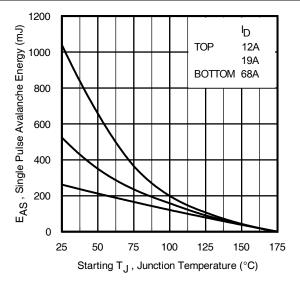


Fig 13. Maximum Safe Operating Area

Fig 14. Maximum Avalanche Energy vs. Temperature

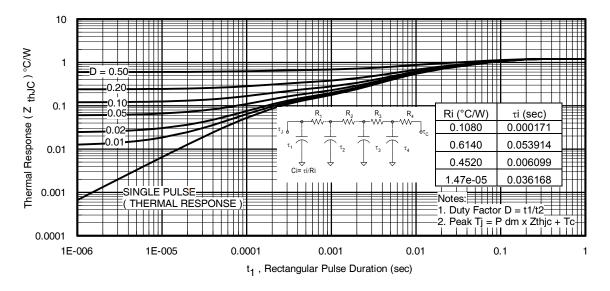


Fig 15. Maximum Effective Transient Thermal Impedance, Junction-to-Case

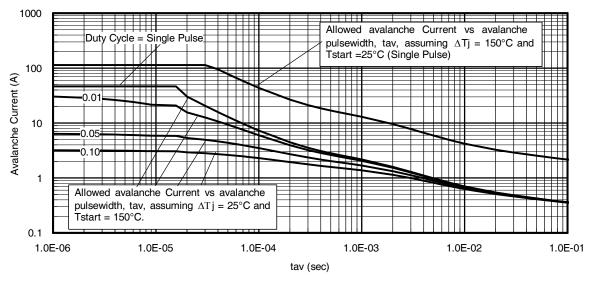


Fig 16. Typical Avalanche Current vs. Pulse Width



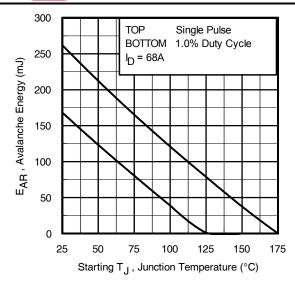


Fig 17. Maximum Avalanche Energy vs. Temperature

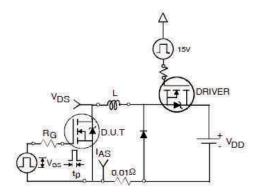


Fig 18a. Unclamped Inductive Test Circuit

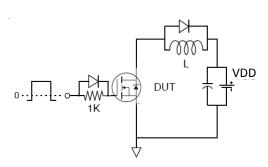


Fig 19a. Gate Charge Test Circuit

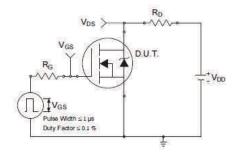


Fig 20a. Switching Time Test Circuit

# Notes on Repetitive Avalanche Curves, Figures 16, 17: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
   Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>jmax</sub>. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T<sub>jmax</sub> is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 18a, 18b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. lav = Allowable avalanche current.
- ΔT = Allowable rise in junction temperature, not to exceed T<sub>jmax</sub> (assumed as 25°C in Figure 16, 17).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 15)

$$\begin{split} P_{D \text{ (ave)}} &= 1/2 \text{ ( } 1.3 \cdot \text{BV} \cdot \text{I}_{av} \text{)} = \Delta \text{T} \text{/ } Z_{thJC} \\ I_{av} &= 2\Delta \text{T} \text{/ [} 1.3 \cdot \text{BV} \cdot Z_{th} \text{]} \\ E_{AS \text{ (AR)}} &= P_{D \text{ (ave)}} \cdot t_{av} \end{split}$$

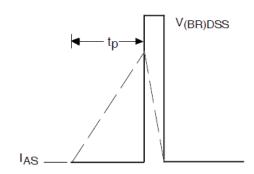


Fig 18b. Unclamped Inductive Waveforms

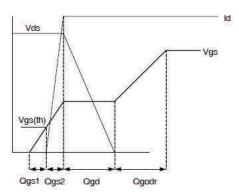


Fig 19b. Gate Charge Waveform

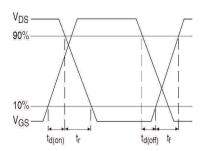
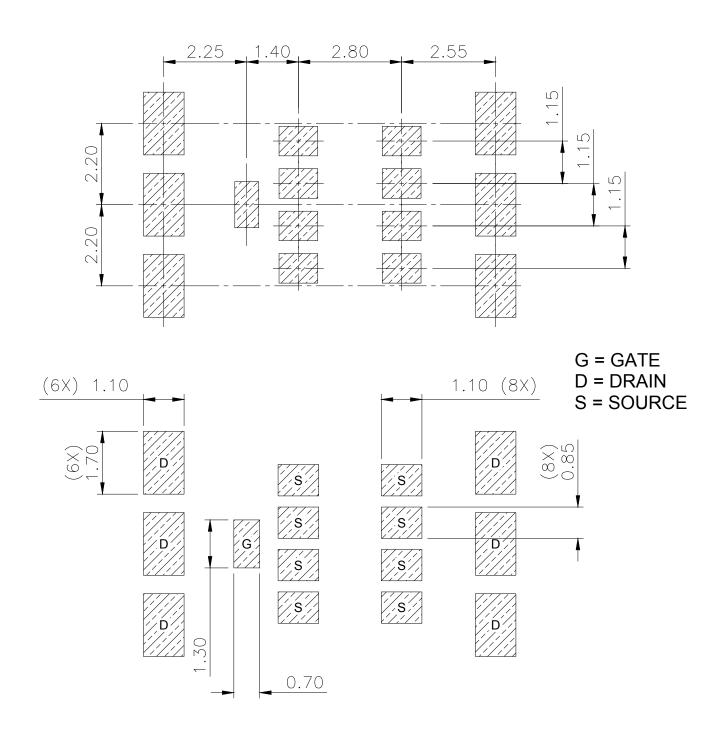


Fig 20b. Switching Time Waveforms



# DirectFET® Board Footprint, L8 (Large Size Can).

Please see DirectFET® application note AN-1035 for all details regarding the assembly of DirectFET® . This includes all recommendations for stencil and substrate designs.

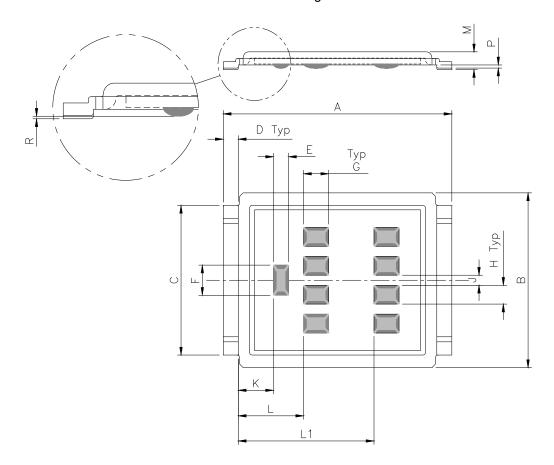


Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>



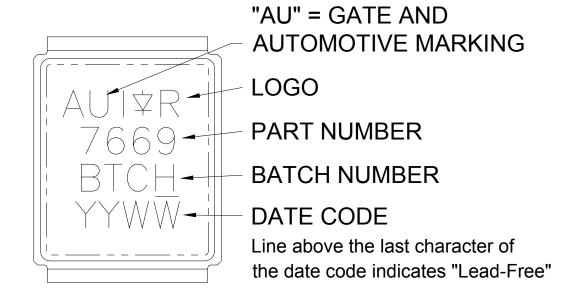
# DirectFET® Outline Dimension, L8 (Large Size Can).

Please see DirectFET® application note AN-1035 for all details regarding the assembly of DirectFET®. This includes all recommendations for stencil and substrate designs.



	DIMENSIONS							
	MET	RIC	IMPE	RIAL				
CODE	MIN	MAX	MIN	MAX				
Α	9.05	9.15	0.356	0.360				
В	6.85	7.10	0.270	0.280				
С	5.90	6.00	0.232	0.236				
D	0.55	0.65	0.022	0.026				
E	0.58	0.62	0.023	0.024				
F	1.18	1.22	0.046	0.048				
G	0.98	1.02	0.039	0.040				
Н	0.73	0.77	0.029	0.030				
J	0.38	0.42	0.015	0.017				
K	1.35	1.45	0.053	0.057				
L	2.55	2.65	0.100	0.104				
L1	5.35	5.45	0.211	0.215				
М	0.68	0.74	0.027	0.029				
Р	0.09	0.17	0.003	0.007				
R	0.02	0.08	0.001	0.003				

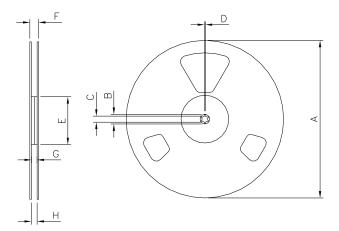
# **DirectFET® Part Marking**



Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

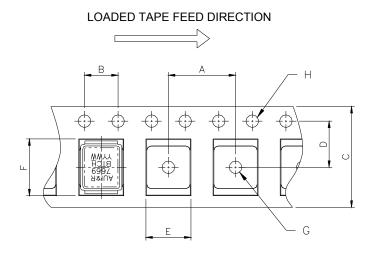


# **DirectFET®** Tape & Reel Dimension (Showing component orientation)



NOTE: Controlling dimensions in mm Std reel quantity is 4000 parts, ordered as AUIRF7669L2TR.

REEL DIMENSIONS						
STANDARD OPTION (QTY 4000)						
	MET	RIC	IMPE	RIAL		
CODE	MIN	MAX	MIN	MAX		
Α	330.00	N.C	12.992	N.C		
В	20.20	N.C	0.795	N.C		
С	12.80	13.20	0.504	0.520		
D	1.50	N.C	0.059	N.C		
E	99.00	100.00	3.900	3.940		
F	N.C	22.40	N.C	0.880		
G	16.40	18.40	0.650	0.720		
Н	15.90	19.40	0.630	0.760		



NOTE: CONTROLLING DIMENSIONS IN MM

DIMENSIONS						
	MET	RIC	IMPERIAL			
CODE	MIN	MAX	MIN	MAX		
Α	11.90	12.10	4.69	0.476		
В	3.90	4.10	0.154	0.161		
С	15.90	16.30	0.623	0.642		
D	7.40	7.60	0.291	0.299		
Е	7.20	7.40	0.283	0.291		
F	9.90	10.10	0.390	0.398		
G	1.50	N.C	0.059	N.C		
Н	1.50	1.60	0.059	0.063		

Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>



#### **Qualification Information**

		Automotive				
Qualification Level		(per AEC-Q101)				
		Comments: This part number(s) passed Automotive qualification. Infineon's				
		Industrial and Consumer qualification level is granted by extension of the higher				
		Automotive level.				
Moisture	Sensitivity Level	DFET2 Large Can	MSL1			
	Machine Model	Class M4 <sup>†</sup>				
	Macrime Model	AEC-Q101-002				
FOD	Lluman Dadu Madal	Class H2 <sup>†</sup>				
ESD	Human Body Model	AEC-Q101-001				
	Observed Davis a Madal	Class C4 <sup>†</sup>				
Charged Device Model		AEC-Q101-005				
RoHS Compliant		Yes				

<sup>†</sup> Highest passing voltage.

## **Revision History**

Date	Comments
11/16/2015	<ul> <li>Updated datasheet with corporate template</li> <li>Corrected ordering table on page 1.</li> <li>Updated Tape and Reel option on page 10</li> </ul>

Published by Infineon Technologies AG 81726 München, Germany © Infineon Technologies AG 2015 All Rights Reserved.

## **IMPORTANT NOTICE**

The information given in this document shall in <u>no event</u> be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie"). With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

For further information on the product, technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies office (<a href="https://www.infineon.com">www.infineon.com</a>).

## **WARNINGS**

Due to technical requirements products may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies office.

Except as otherwise explicitly approved by Infineon Technologies in a written document signed by authorized representatives of Infineon Technologies, Infineon Technologies' products may <u>not</u> be used in any applications where a failure of the product or any consequences of the use thereof can reasonably be expected to result in personal injury.